



Title of Change:	Update Typical Reading of Tr and Tf in Datasheet for 40V T6 products.		
Effective date:	11 May 2017		
Contact information:	Contact your local ON Semiconductor Sales Office or guokun.yeng@onsemi.com		
Type of notification:	ON Semiconductor will consider this change accepted.		
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☒ Other <u>Datasheet</u>		
Change Sub-Category(s): ☐ Manufacturing Site Change/Addition ☐ Manufacturing Process Change ☐ Material Change ☐ Product specific change ☒ Datasheet/Product Doc change ☐ Shipping/Packaging/Marking ☐ Other: _____			
Sites Affected: ☐ All site(s) ☐ not applicable ☒ ON Semiconductor site(s) : ON Seremban, Malaysia ☐ External Foundry/Subcon site(s)			
Description and Purpose: This Product Bulletin is announcing that ON Semiconductor is updating datasheet for below products. The change is to update typical reading of switching parameter, Tr and Tf to reflect the actual device performance. ON is improving the measurement method with reduce influence of parasitic inductance in the measurement PCB design.			
List of Affected Standard Parts: NTMFS5C423NLT1G NTMFS5C423NLT3G NTMFS5C442NLT1G NTMFS5C442NLT3G NTMFS5C442NLTT1G NTMFS5C442NLTT3G NTMFS5C442NLTWFT1G NTMFS5C442NLTWFT3G NTMFS5C460NLT1G NTMFS5C460NLT3G			